



Application Serial No. 09/905,286
Filing Date July 13, 2001
Inventor Basceri et al.
Assignee Micron Technology, Inc.
Group Art Unit 1762
Examiner E. Fuller
Attorney's Docket No. MI22-1724
Title: Chemical Vapor Deposition Methods of Forming Barium Strontium Titanate
Comprising Dielectric Layers

INFORMATION DISCLOSURE STATEMENT

To: Mail Stop RCE
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

From: Jennifer J. Taylor, Ph.D.
(Tel. 509-624-4276; Fax 509-838-3424)
Wells St. John P.S.
601 W. First Avenue, Suite 1300
Spokane, WA 99201-3828

Dear Sir:

The Examiner's attention is directed to the references which are listed on
the attached Form PTO-1449 and copies of which are attached.

Citation of these references is respectfully requested.

Respectfully submitted,

Dated: July 9, 2004

By: Jennifer J. Taylor
Jennifer J. Taylor
Reg. No. 48,711

Form PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
MI22-1724SERIAL NO.
09/905,286LIST OF ART CITED BY APPLICANT
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Cem Basceri et al.FILING DATE
July 13, 2001GROUP
1762

U.S. PATENT DOCUMENTS

| *Examiner Initial | Document Number | Date | Name | Class | Subclass | Filing Date If Appropriate |
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| AA | 4,261,698 | 04/81 | Carr et al. | | | |
| AB | 4,691,662 | 09/87 | Roppel et al. | | | |
| AC | 5,261,961 | 11/93 | Takasu et al. | | | |
| AD | 5,270,241 | 12/93 | Dennison et al. | | | |
| AE | 5,312,783 | 05/94 | Takasaki et al. | | | |
| AF | 5,392,189 | 02/95 | Fazan et al. | | | |
| AG | 5,395,771 | 03/95 | Nakato | | | |
| AH | 5,468,687 | 11/95 | Carl et al. | | | |
| AI | 5,525,156 | 06/96 | Manada et al. | | | |
| AJ | 5,614,018 | 03/97 | Azuma et al. | | | |
| AK | 5,656,329 | 08/97 | Hampden-Smith | | | |
| AL | 5,663,089 | 09/97 | Tomozawa et al. | | | |

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| | | | | | | Yes | No |
| AM | EP 0 030 798 | 06/81 | EPO | | | | |
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| AP | EP 0 388 957 A2 | 09/90 | EPO | | | | |
| AQ | JP2250970 | 10/90 | Japan | | | | |

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

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|----------|--|-----------------|--|--|--|--|
| AR | Aoyama et al., <i>Leakage Current Mechanism of Amorphous and Polycrystalline Ta₂O₅ Films Grown by Chemical Vapor Deposition</i> , 143 J. ELECTROCHEM SOC., No. 3, pp 977-983 (March 1996). | | | | | |
| | | | | | | |
| AS | Stemmer et al., <i>Accommodation of nonstoichiometry in (100) fiber-textured (Ba_xSr_{1-x})Ti_{1-y}O_{3+z} thin films grown by chemical vapor deposition</i> , 74 APPL. PHYS. LETT., No. 17, pp. 2432-2434 (26 April 1999). | | | | | |
| | | | | | | |
| AT | Streiffer et al., <i>Ferroelectricity in thin films: The dielectric response of fiber-textured (Ba_xSr_{1-x})Ti_{1-y}O_{3+z} thin films grown by chemical vapor deposition</i> , 86 J. APPL. PHYS. No. 8, pp. 4565-4575 (15 October 1999). | | | | | |
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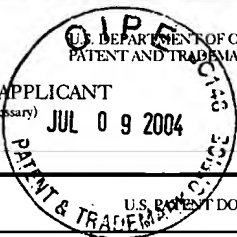
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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PATENT AND TRADEMARK OFFICE

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ATTY. DOCKET NO.
M122-1724

SERIAL NO.
09/905,286

APPLICANT
Cem Basceri et al.

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| | AD | 5,736,759 | 04/98 | Hausaalter | | | |
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| | AM | 04-24922 | 01/92 | Japan | | | | |
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| | AO | 04-180566 | 06/92 | Japan | | | | |
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| | AQ | EP 0 810 666 A1 | 12/97 | EPO | | | | |

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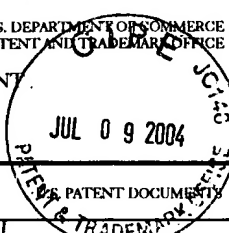
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| | AA | 6,566,147 B2 | 05/03 | Basceri et al. | | | |
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| | AQ | | | | | | | |

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